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Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC G4
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	1.7GHz
Co-Processors/DSP	Multimedia; SIMD
RAM Controllers	-
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	-
SATA	-
USB	-
Voltage - I/O	1.5V, 1.8V, 2.5V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	360-CLGA, FCCLGA
Supplier Device Package	360-FCCLGA (25x25)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mc7448vs1700ld

2 Features

This section summarizes features of the MPC7448 implementation.

Major features of the MPC7448 are as follows:

- High-performance, superscalar microprocessor
 - Up to four instructions can be fetched from the instruction cache at a time.
 - Up to three instructions plus a branch instruction can be dispatched to the issue queues at a time.
 - Up to 12 instructions can be in the instruction queue (IQ).
 - Up to 16 instructions can be at some stage of execution simultaneously.
 - Single-cycle execution for most instructions
 - One instruction per clock cycle throughput for most instructions
 - Seven-stage pipeline control
- Eleven independent execution units and three register files
 - Branch processing unit (BPU) features static and dynamic branch prediction
 - 128-entry (32-set, four-way set-associative) branch target instruction cache (BTIC), a cache of branch instructions that have been encountered in branch/loop code sequences. If a target instruction is in the BTIC, it is fetched into the instruction queue a cycle sooner than it can be made available from the instruction cache. Typically, a fetch that hits the BTIC provides the first four instructions in the target stream.
 - 2048-entry branch history table (BHT) with 2 bits per entry for four levels of prediction—not taken, strongly not taken, taken, and strongly taken
 - Up to three outstanding speculative branches
 - Branch instructions that do not update the count register (CTR) or link register (LR) are often removed from the instruction stream.
 - Eight-entry link register stack to predict the target address of Branch Conditional to Link Register (**bclr**) instructions
 - Four integer units (IUs) that share 32 GPRs for integer operands
 - Three identical IUs (IU1a, IU1b, and IU1c) can execute all integer instructions except multiply, divide, and move to/from special-purpose register instructions.
 - IU2 executes miscellaneous instructions, including the CR logical operations, integer multiplication and division instructions, and move to/from special-purpose register instructions.
 - Five-stage FPU and 32-entry FPR file
 - Fully IEEE Std. 754™-1985-compliant FPU for both single- and double-precision operations
 - Supports non-IEEE mode for time-critical operations
 - Hardware support for denormalized numbers
 - Thirty-two 64-bit FPRs for single- or double-precision operands

- Efficient data flow
 - Although the VR/LSU interface is 128 bits, the L1/L2 bus interface allows up to 256 bits.
 - The L1 data cache is fully pipelined to provide 128 bits/cycle to or from the VRs.
 - The L2 cache is fully pipelined to provide 32 bytes per clock every other cycle to the L1 caches.
 - As many as 16 out-of-order transactions can be present on the MPX bus.
 - Store merging for multiple store misses to the same line. Only coherency action taken (address-only) for store misses merged to all 32 bytes of a cache block (no data tenure needed).
 - Three-entry finished store queue and five-entry completed store queue between the LSU and the L1 data cache
 - Separate additional queues for efficient buffering of outbound data (such as castouts and write-through stores) from the L1 data cache and L2 cache
- Multiprocessing support features include the following:
 - Hardware-enforced, MESI cache coherency protocols for data cache
 - Load/store with reservation instruction pair for atomic memory references, semaphores, and other multiprocessor operations
- Power and thermal management
 - Dynamic frequency switching (DFS) feature allows processor core frequency to be halved or quartered through software to reduce power consumption.
 - The following three power-saving modes are available to the system:
 - Nap—Instruction fetching is halted. Only the clocks for the time base, decremter, and JTAG logic remain running. The part goes into the doze state to snoop memory operations on the bus and then back to nap using a QREQ/QACK processor-system handshake protocol.
 - Sleep—Power consumption is further reduced by disabling bus snooping, leaving only the PLL in a locked and running state. All internal functional units are disabled.
 - Deep sleep—When the part is in the sleep state, the system can disable the PLL. The system can then disable the SYSCLK source for greater system power savings. Power-on reset procedures for restarting and relocking the PLL must be followed upon exiting the deep sleep state.
 - Instruction cache throttling provides control of instruction fetching to limit device temperature.
 - A new temperature diode that can determine the temperature of the microprocessor
- Performance monitor can be used to help debug system designs and improve software efficiency.
- In-system testability and debugging features through JTAG boundary-scan capability
- Testability
 - LSSD scan design
 - IEEE Std. 1149.1™ JTAG interface

Table 1. Microarchitecture Comparison (continued)

Microarchitectural Specs	MPC7448	MPC7447A	MPC7447	MPC7445	MPC7441
Execution Unit Timings (Latency-Throughput)					
Aligned load (integer, float, vector)	3-1, 4-1, 3-1				
Misaligned load (integer, float, vector)	4-2, 5-2, 4-2				
L1 miss, L2 hit latency with ECC (data/instruction)	12/16	—			
L1 miss, L2 hit latency without ECC (data/instruction)	11/15	9/13			
SFX (add, sub, shift, rot, cmp, logicals)	1-1				
Integer multiply (32 × 8, 32 × 16, 32 × 32)	4-1, 4-1, 5-2				
Scalar float	5-1				
VSFX (vector simple)	1-1				
VCFX (vector complex)	4-1				
VFPU (vector float)	4-1				
VPER (vector permute)	2-1				
MMUs					
TLBs (instruction and data)	128-entry, 2-way				
Tablewalk mechanism	Hardware + software				
Instruction BATs/data BATs	8/8	8/8	8/8	8/8	4/4
L1 I Cache/D Cache Features					
Size	32K/32K				
Associativity	8-way				
Locking granularity	Way				
Parity on I cache	Word				
Parity on D cache	Byte				
Number of D cache misses (load/store)	5/2	5/1			
Data stream touch engines	4 streams				
On-Chip Cache Features					
Cache level	L2				
Size/associativity	1-Mbyte/ 8-way	512-Kbyte/8-way	256-Kbyte/8-way		
Access width	256 bits				
Number of 32-byte sectors/line	2	2			
Parity tag	Byte	Byte			
Parity data	Byte	Byte			
Data ECC	64-bit	—			
Thermal Control					
Dynamic frequency switching divide-by-two mode	Yes	Yes	No	No	No
Dynamic frequency switching divide-by-four mode	Yes	No	No	No	No
Thermal diode	Yes	Yes	No	No	No

4 General Parameters

The following list summarizes the general parameters of the MPC7448:

Technology	90 nm CMOS SOI, nine-layer metal	
Die size	8.0 mm × 7.3 mm	
Transistor count	90 million	
Logic design	Mixed static and dynamic	
Packages	Surface mount 360 ceramic ball grid array (HCTE)	
	Surface mount 360 ceramic land grid array (HCTE)	
	Surface mount 360 ceramic ball grid array with lead-free spheres (HCTE)	
Core power supply	1.30 V	(1700 MHz device)
	1.25 V	(1600 MHz device)
	1.20 V	(1420 MHz device)
	1.15 V	(1000 MHz device)
I/O power supply	1.5 V, 1.8 V, or 2.5 V	

5 Electrical and Thermal Characteristics

This section provides the AC and DC electrical specifications and thermal characteristics for the MPC7448.

5.1 DC Electrical Characteristics

The tables in this section describe the MPC7448 DC electrical characteristics. [Table 2](#) provides the absolute maximum ratings. See [Section 9.2, “Power Supply Design and Sequencing,”](#) for power sequencing requirements.

Table 2. Absolute Maximum Ratings ¹

Characteristic		Symbol	Maximum Value	Unit	Notes
Core supply voltage		V_{DD}	-0.3 to 1.4	V	2
PLL supply voltage		AV_{DD}	-0.3 to 1.4	V	2
Processor bus supply voltage	I/O Voltage Mode = 1.5 V	OV_{DD}	-0.3 to 1.8	V	3
	I/O Voltage Mode = 1.8 V		-0.3 to 2.2		3
	I/O Voltage Mode = 2.5 V		-0.3 to 3.0		3
Input voltage	Processor bus	V_{in}	-0.3 to $OV_{DD} + 0.3$	V	4
	JTAG signals	V_{in}	-0.3 to $OV_{DD} + 0.3$	V	
Storage temperature range		T_{stg}	- 55 to 150	°C	

Notes:

1. Functional and tested operating conditions are given in [Table 4](#). Absolute maximum ratings are stress ratings only and functional operation at the maximums is not guaranteed. Stresses beyond those listed may affect device reliability or cause permanent damage to the device.
2. See [Section 9.2, “Power Supply Design and Sequencing”](#) for power sequencing requirements.
3. Bus must be configured in the corresponding I/O voltage mode; see [Table 3](#).
4. **Caution:** V_{in} must not exceed OV_{DD} by more than 0.3 V at any time including during power-on reset except as allowed by the overshoot specifications. V_{in} may overshoot/undershoot to a voltage and for a maximum duration as shown in [Figure 2](#).

Table 5 provides the package thermal characteristics for the MPC7448. For more information regarding thermal management, see Section 9.7, “Power and Thermal Management Information.”

Table 5. Package Thermal Characteristics¹

Characteristic	Symbol	Value	Unit	Notes
Junction-to-ambient thermal resistance, natural convection, single-layer (1s) board	$R_{\theta JA}$	26	•C/W	2, 3
Junction-to-ambient thermal resistance, natural convection, four-layer (2s2p) board	$R_{\theta JMA}$	19	•C/W	2, 4
Junction-to-ambient thermal resistance, 200 ft/min airflow, single-layer (1s) board	$R_{\theta JMA}$	22	•C/W	2, 4
Junction-to-ambient thermal resistance, 200 ft/min airflow, four-layer (2s2p) board	$R_{\theta JMA}$	16	•C/W	2, 4
Junction-to-board thermal resistance	$R_{\theta JB}$	11	•C/W	5
Junction-to-case thermal resistance	$R_{\theta JC}$	< 0.1	•C/W	6

Notes:

1. Refer to Section 9.7, “Power and Thermal Management Information,” for details about thermal management.
2. Junction temperature is a function of on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, airflow, power dissipation of other components on the board, and board thermal resistance.
3. Per JEDEC JESD51-2 with the single-layer board horizontal
4. Per JEDEC JESD51-6 with the board horizontal
5. Thermal resistance between the die and the printed-circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
6. This is the thermal resistance between die and case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1) with the calculated case temperature. The actual value of $R_{\theta JC}$ for the part is less than 0.1°C/W.

Table 6 provides the DC electrical characteristics for the MPC7448.

Table 6. DC Electrical Specifications

At recommended operating conditions. See Table 4.

Characteristic	Nominal Bus Voltage ¹	Symbol	Min	Max	Unit	Notes
Input high voltage (all inputs)	1.5	V_{IH}	$OV_{DD} \times 0.65$	$OV_{DD} + 0.3$	V	2
	1.8		$OV_{DD} \times 0.65$	$OV_{DD} + 0.3$		
	2.5		1.7	$OV_{DD} + 0.3$		
Input low voltage (all inputs)	1.5	V_{IL}	-0.3	$OV_{DD} \times 0.35$	V	2
	1.8		-0.3	$OV_{DD} \times 0.35$		
	2.5		-0.3	0.7		
Input leakage current, all signals except BVSELO, LSSD_MODE, TCK, TDI, TMS, TRST: $V_{in} = OV_{DD}$ $V_{in} = GND$	—	I_{in}	—	50 - 50	μA	2, 3
Input leakage current, BVSELO, LSSD_MODE, TCK, TDI, TMS, TRST: $V_{in} = OV_{DD}$ $V_{in} = GND$	—	I_{in}	—	50 - 2000	μA	2, 6

5.2 AC Electrical Characteristics

This section provides the AC electrical characteristics for the MPC7448. After fabrication, functional parts are sorted by maximum processor core frequency as shown in [Section 5.2.1, “Clock AC Specifications,”](#) and tested for conformance to the AC specifications for that frequency. The processor core frequency, determined by the bus (SYSCLK) frequency and the settings of the PLL_CFG[0:5] signals, can be dynamically modified using dynamic frequency switching (DFS). Parts are sold by maximum processor core frequency; see [Section 11, “Part Numbering and Marking,”](#) for information on ordering parts. DFS is described in [Section 9.7.5, “Dynamic Frequency Switching \(DFS\).”](#)

5.2.1 Clock AC Specifications

[Table 8](#) provides the clock AC timing specifications as defined in [Figure 3](#) and represents the tested operating frequencies of the devices. The maximum system bus frequency, f_{SYSCLK} , given in [Table 8](#), is considered a practical maximum in a typical single-processor system. This does not exclude multi-processor systems, but these typically require considerably more design effort to achieve the maximum rated bus frequency. The actual maximum SYSCLK frequency for any application of the MPC7448 will be a function of the AC timings of the microprocessor(s), the AC timings for the system controller, bus loading, circuit board topology, trace lengths, and so forth, and may be less than the value given in [Table 8](#).

Figure 4 provides the AC test load for the MPC7448.

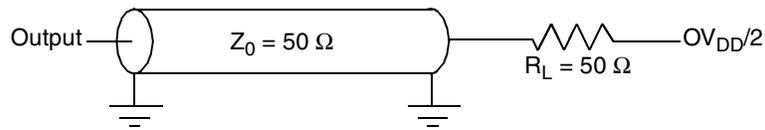


Figure 4. AC Test Load

Figure 5 provides the $\overline{\text{BMODE}}[0:1]$ input timing diagram for the MPC7448. These mode select inputs are sampled once before and once after $\overline{\text{HRESET}}$ negation.

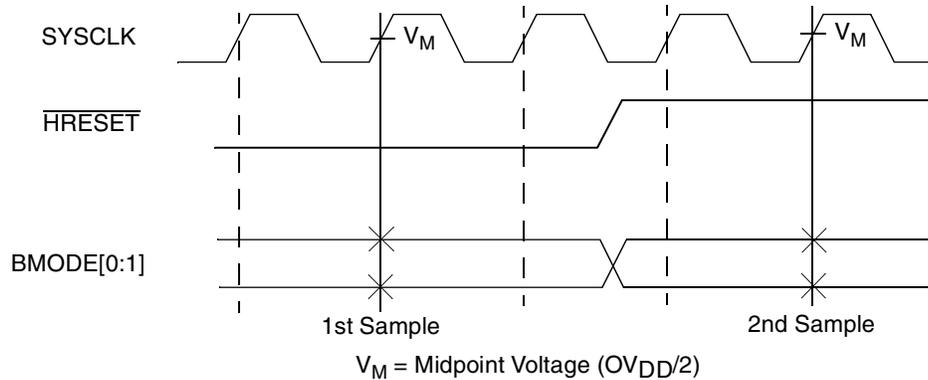


Figure 5. $\overline{\text{BMODE}}[0:1]$ Input Sample Timing Diagram

Figure 6 provides the input/output timing diagram for the MPC7448.

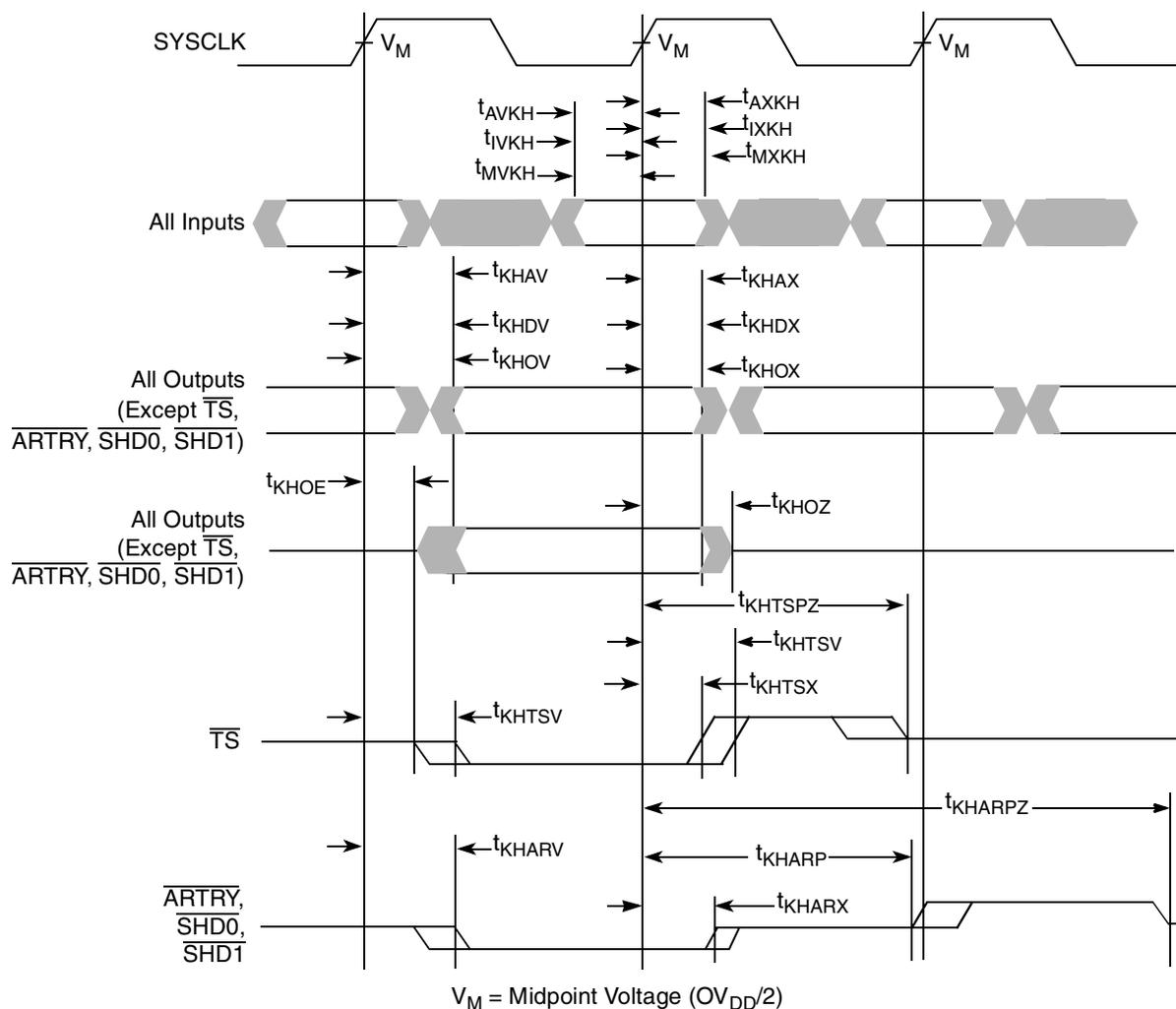


Figure 6. Input/Output Timing Diagram

Figure 7 provides the AC test load for TDO and the boundary-scan outputs of the MPC7448.

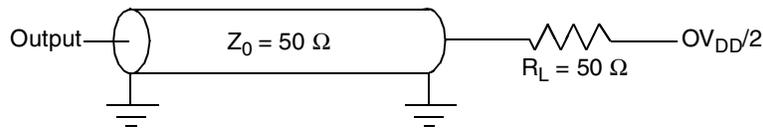


Figure 7. Alternate AC Test Load for the JTAG Interface

Figure 8 provides the JTAG clock input timing diagram.

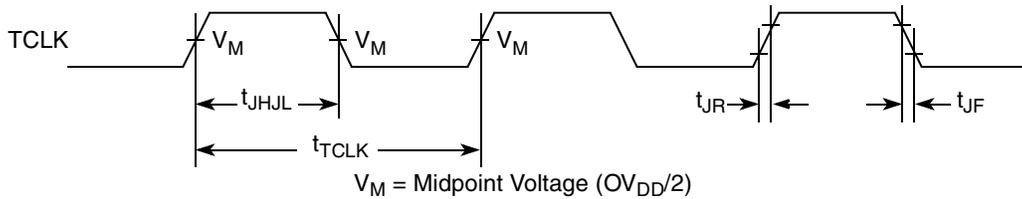


Figure 8. JTAG Clock Input Timing Diagram

Figure 9 provides the $\overline{\text{TRST}}$ timing diagram.

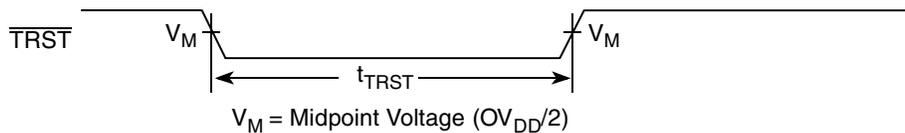


Figure 9. $\overline{\text{TRST}}$ Timing Diagram

Figure 10 provides the boundary-scan timing diagram.

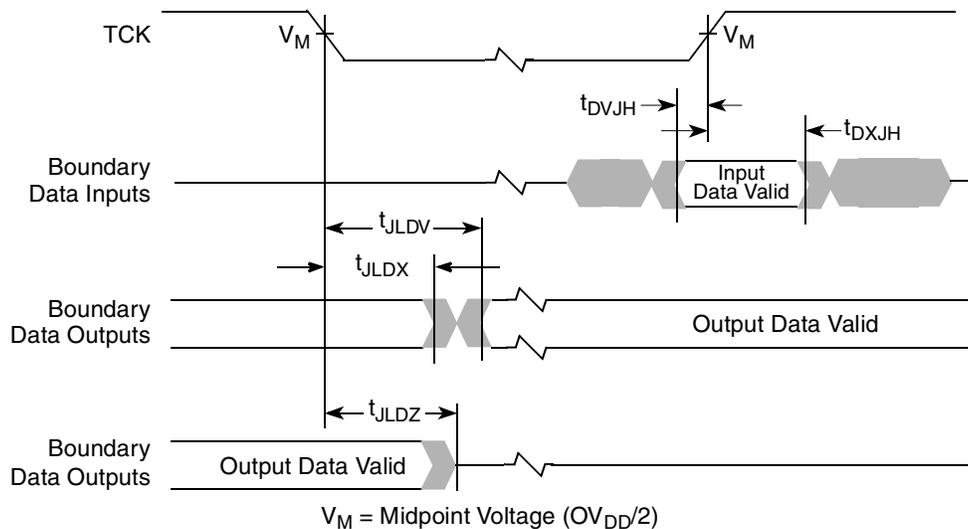


Figure 10. Boundary-Scan Timing Diagram

7 Pinout Listings

Table 11 provides the pinout listing for the MPC7448, 360 HCTE package. The pinouts of the MPC7448 and MPC7447A are compatible, but the requirements regarding the use of the additional power and ground pins have changed. The MPC7448 requires these pins be connected to the appropriate power or ground plane to achieve high core frequencies; see Section 9.3, “Connection Recommendations,” for additional information. As a result, these pins should be connected in all new designs.

Additionally, the MPC7448 may be populated on a board designed for a MPC7447 (or MPC7445 or MPC7441), provided the core voltage can be made to match the requirements in Table 4 and all pins defined as ‘no connect’ for the MPC7447 are unterminated, as required by the *MPC7457 RISC Microprocessor Hardware Specifications*. The MPC7448 uses pins previously marked ‘no connect’ for the temperature diode pins and for additional power and ground connections. The additional power and ground pins are required to achieve high core frequencies and core frequency will be limited if they are not connected; see Section 9.3, “Connection Recommendations,” for additional information. Because these ‘no connect’ pins in the MPC7447 360 pin package are not driven in functional mode, an MPC7447 can be populated in an MPC7448 board.

NOTE

Caution must be exercised when performing boundary scan test operations on a board designed for an MPC7448, but populated with an MPC7447 or earlier device. This is because in the MPC7447 it is possible to drive the latches associated with the former ‘no connect’ pins in the MPC7447, potentially causing contention on those pins. To prevent this, ensure that these pins are not connected on the board or, if they are connected, ensure that the states of internal MPC7447 latches do not cause these pins to be driven during board testing.

For the MPC7448, pins that were defined as the TEST[0:4] factory test signal group on the MPC7447A and earlier devices have been assigned new functions. For most of these, the termination recommendations for the TEST[0:4] pins of the MPC7447A are compatible with the MPC7448 and will allow correct operation with no performance loss. The exception is BVSEL1 (TEST3 on the MPC7447A and earlier devices), which may require a different termination depending which I/O voltage mode is desired; see Table 3 for more information.

NOTE

This pinout is not compatible with the MPC750, MPC7400, or MPC7410 360 BGA package.

8 Package Description

The following sections provide the package parameters and mechanical dimensions for the HCTE package.

8.1 Package Parameters for the MPC7448, 360 HCTE BGA

The package parameters are as provided in the following list. The package type is 25 × 25 mm, 360-lead high coefficient of thermal expansion ceramic ball grid array (HCTE).

Package outline	25 × 25 mm
Interconnects	360 (19 × 19 ball array – 1)
Pitch	1.27 mm (50 mil)
Minimum module height	2.32 mm
Maximum module height	2.80 mm
Ball diameter	0.89 mm (35 mil)
Coefficient of thermal expansion	12.3 ppm/°C

8.3 Package Parameters for the MPC7448, 360 HCTE LGA

The package parameters are as provided in the following list. The package type is 25 × 25 mm, 360 pin high coefficient of thermal expansion ceramic land grid array (HCTE).

Package outline	25 × 25 mm
Interconnects	360 (19 × 19 ball array – 1)
Pitch	1.27 mm (50 mil)
Minimum module height	1.52 mm
Maximum module height	1.80 mm
Pad diameter	0.89 mm (35 mil)
Coefficient of thermal expansion	12.3 ppm/°C

8.4 Mechanical Dimensions for the MPC7448, 360 HCTE LGA

Figure 13 provides the mechanical dimensions and bottom surface nomenclature for the MPC7448, 360 HCTE LGA package.

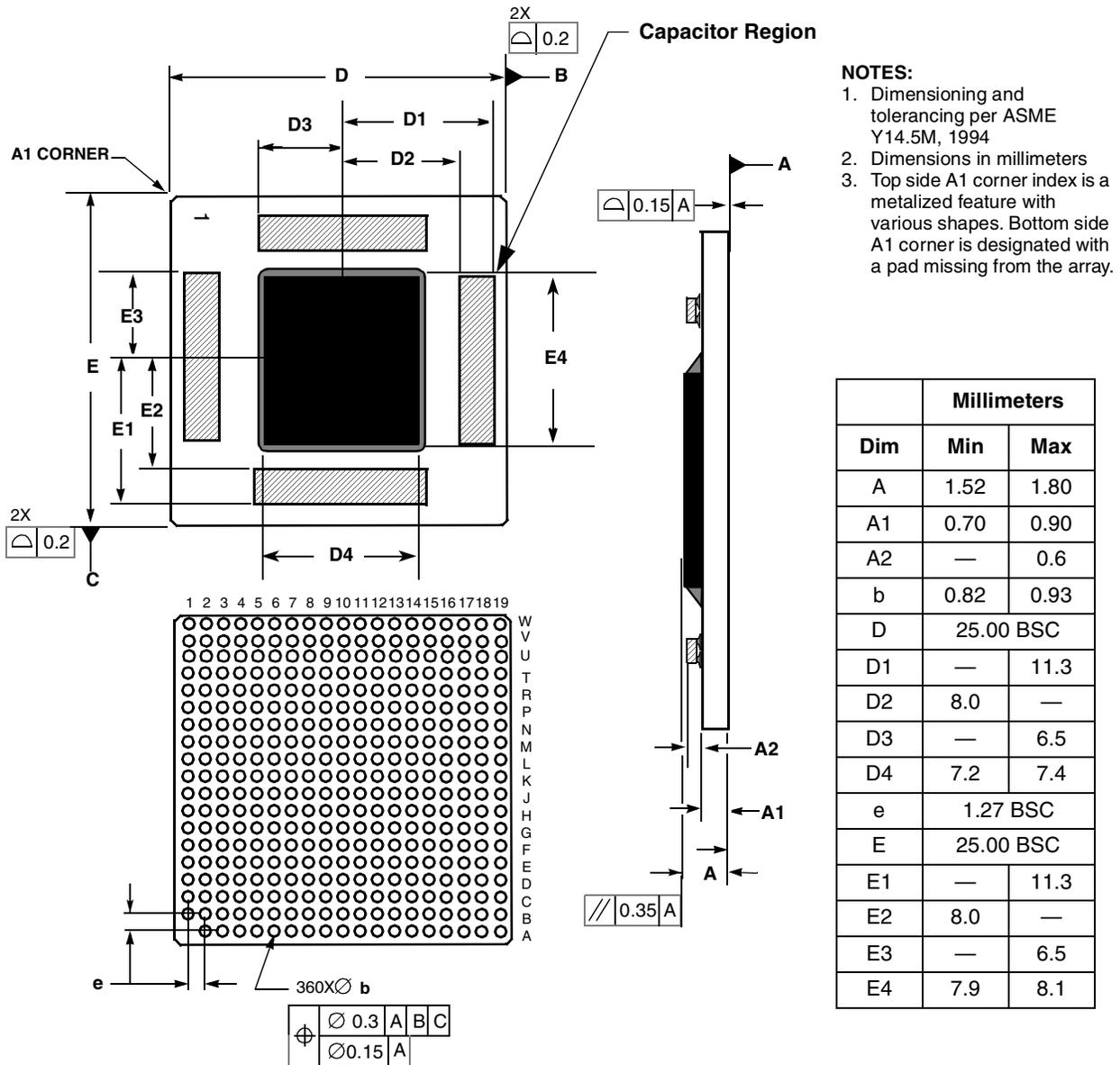


Figure 14. Mechanical Dimensions and Bottom Surface Nomenclature for the MPC7448, 360 HCTE LGA Package

8.6 Mechanical Dimensions for the MPC7448, 360 HCTE RoHS-Compliant BGA

Figure 13 provides the mechanical dimensions and bottom surface nomenclature for the MPC7448, 360 HCTE BGA package with RoHS-compliant lead-free spheres.

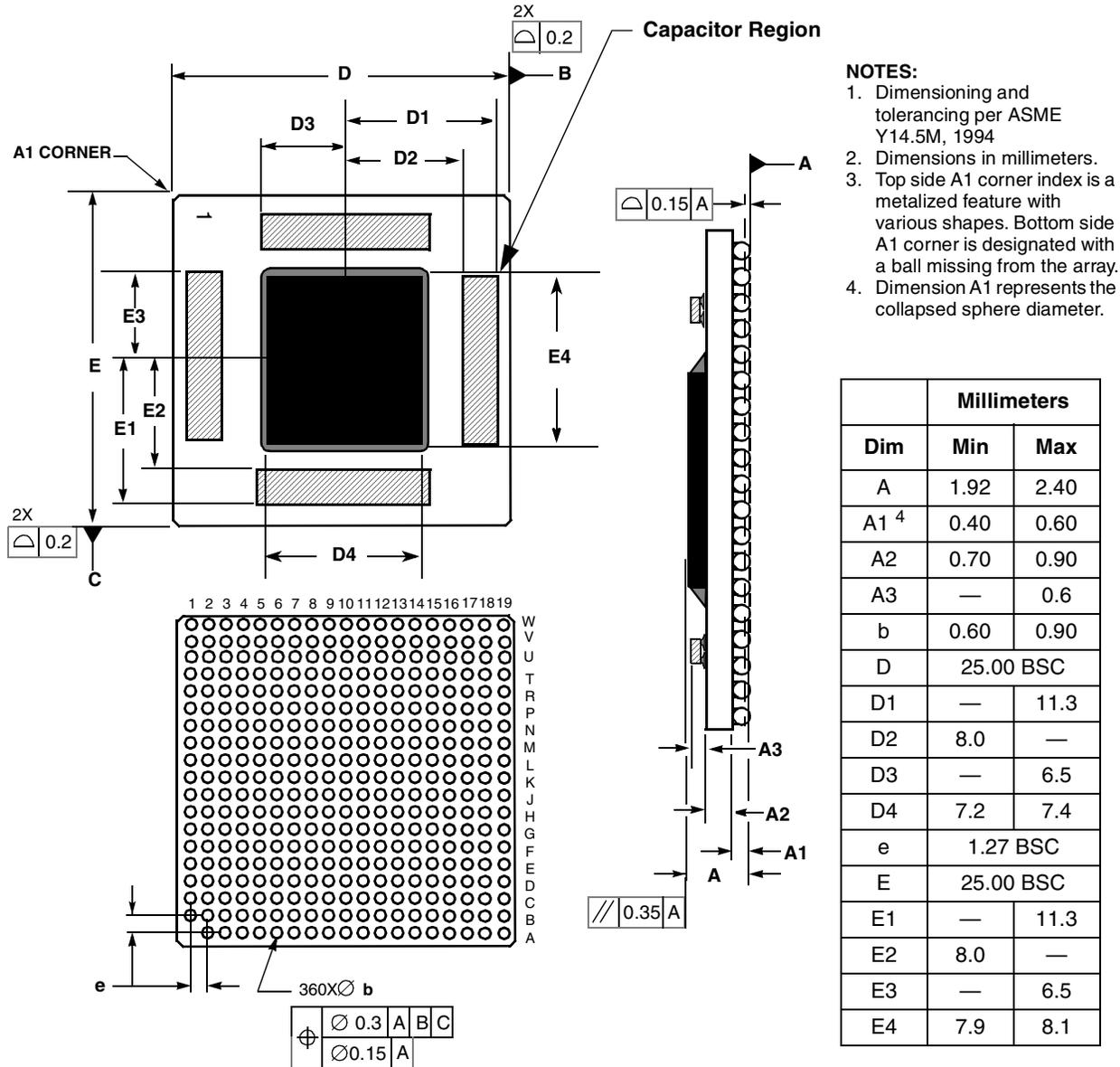


Figure 15. Mechanical Dimensions and Bottom Surface Nomenclature for the MPC7448, 360 HCTE RoHS-Compliant BGA Package

Table 12. MPC7448 Microprocessor PLL Configuration Example (continued)

PLL_CFG[0:5]	Example Core and VCO Frequency in MHz										
	Bus-to-Core Multiplier ⁵	Core-to-VCO Multiplier ⁵	Bus (SYSCLK) Frequency								
			33.3 MHz	50 MHz	66.6 MHz	75 MHz	83 MHz	100 MHz	133 MHz	167 MHz	200 MHz
100110	11x	1x			733	825	913	1100	1467		
000000	11.5x	1x			766	863	955	1150	1533		
101110	12x	1x		600	800	900	996	1200	1600		
111110	12.5x	1x		625	833	938	1038	1250	1667		
010110	13x	1x		650	865	975	1079	1300			
111000	13.5x	1x		675	900	1013	1121	1350			
110010	14x	1x		700	933	1050	1162	1400			
000110	15x	1x		750	1000	1125	1245	1500			
110110	16x	1x		800	1066	1200	1328	1600			
000010	17x	1x		850	1132	1275	1417	1700			
001010	18x	1x	600	900	1200	1350	1500				
001110	20x	1x	667	1000	1332	1500	1666				
010010	21x	1x	700	1050	1399	1575					
011010	24x	1x	800	1200	1600						
111010	28x	1x	933	1400							
001100	PLL bypass		PLL off, SYSCLK clocks core circuitry directly								
111100	PLL off		PLL off, no core clocking occurs								

Notes:

1. PLL_CFG[0:5] settings not listed are reserved.
2. The sample bus-to-core frequencies shown are for reference only. Some PLL configurations may select bus, core, or VCO frequencies which are not useful, not supported, or not tested for by the MPC7448; see [Section 5.2.1, "Clock AC Specifications,"](#) for valid SYSCLK, core, and VCO frequencies.
3. In PLL-bypass mode, the SYSCLK input signal clocks the internal processor directly and the PLL is disabled. However, the bus interface unit requires a 2x clock to function. Therefore, an additional signal, EXT_QUAL, must be driven at half the frequency of SYSCLK and offset in phase to meet the required input setup t_{IVKH} and hold time t_{IXKH} (see [Table 9](#)). The result will be that the processor bus frequency will be one-half SYSCLK, while the internal processor is clocked at SYSCLK frequency. This mode is intended for factory use and emulator tool use only.
Note: The AC timing specifications given in this document do not apply in PLL-bypass mode.
4. In PLL-off mode, no clocking occurs inside the MPC7448 regardless of the SYSCLK input.
5. Applicable when DFS modes are disabled. These multipliers change when operating in a DFS mode. See [Section 9.7.5, "Dynamic Frequency Switching \(DFS\)"](#) for more information.
6. Bus-to-core multipliers less than 5x require that assertion of AACK be delayed by one or two bus cycles to allow the processor to generate a response to a snooped transaction. See the *MPC7450 RISC Microprocessor Reference Manual* for more information.

These requirements are shown graphically in [Figure 16](#).

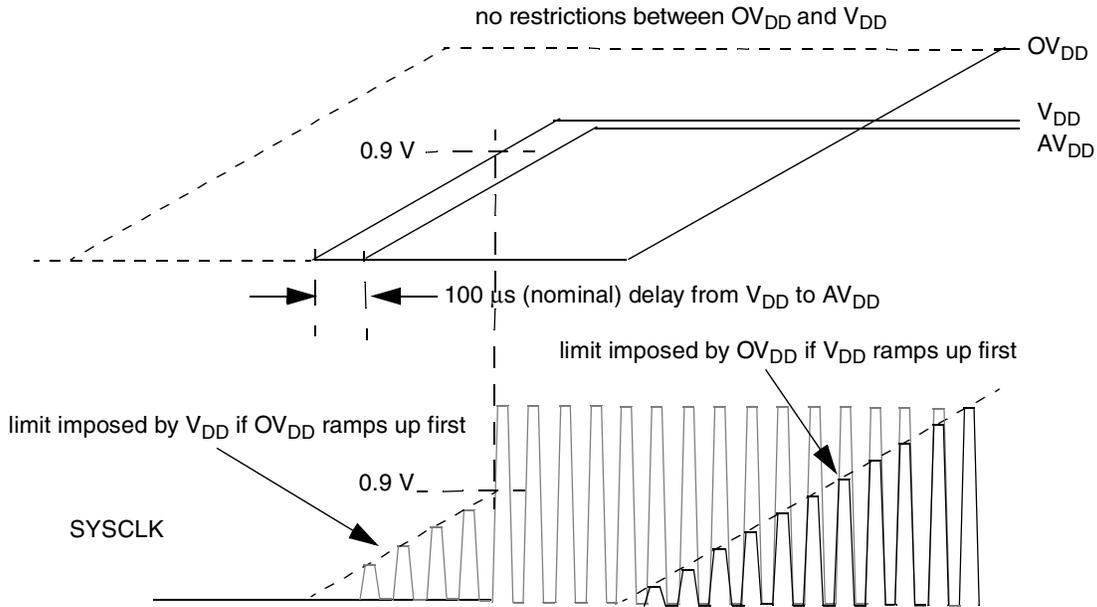


Figure 16. MPC7448 Power Up Sequencing Requirements

Certain stipulations also apply to the manner in which the power rails of the MPC7448 power down, as follows:

- OV_{DD} may ramp down any time before or after V_{DD} .
- The voltage at the SYSCLK input must not exceed V_{DD} once V_{DD} has ramped down below 0.9 V.
- The voltage at the SYSCLK input must not exceed OV_{DD} by more 20% during transients (see overshoot/undershoot specifications in [Figure 2](#)) or 0.3 V DC (see [Table 2](#)) at any time.

9.7 Power and Thermal Management Information

This section provides thermal management information for the high coefficient of thermal expansion (HCTE) package for air-cooled applications. Proper thermal control design is primarily dependent on the system-level design—the heat sink, airflow, and thermal interface material. The MPC7448 implements several features designed to assist with thermal management, including DFS and the temperature diode. DFS reduces the power consumption of the device by reducing the core frequency; see [Section 9.7.5.1, “Power Consumption with DFS Enabled,”](#) for specific information regarding power reduction and DFS. The temperature diode allows an external device to monitor the die temperature in order to detect excessive temperature conditions and alert the system; see [Section 9.7.4, “Temperature Diode,”](#) for more information.

To reduce the die-junction temperature, heat sinks may be attached to the package by several methods—spring clip to holes in the printed-circuit board or package, and mounting clip and screw assembly (see [Figure 22](#)); however, due to the potential large mass of the heat sink, attachment through the printed-circuit board is suggested. In any implementation of a heat sink solution, the force on the die should not exceed ten pounds (45 Newtons).

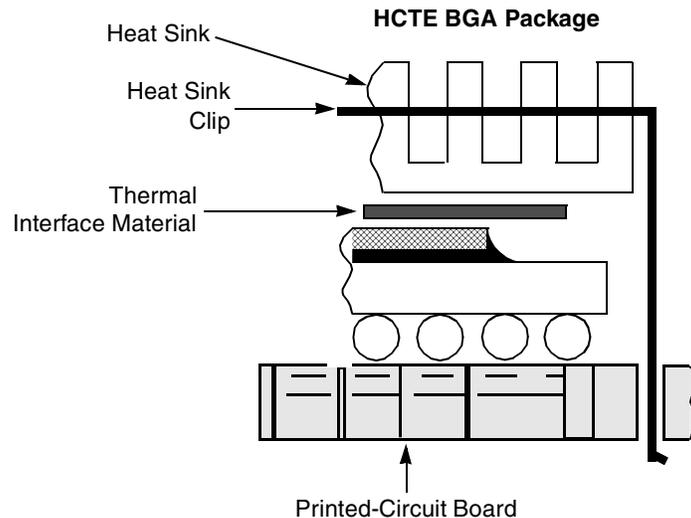


Figure 22. BGA Package Exploded Cross-Sectional View with Several Heat Sink Options

NOTE

A clip on heat sink is not recommended for LGA because there may not be adequate clearance between the device and the circuit board. A through-hole solution is recommended, as shown in [Figure 23](#).

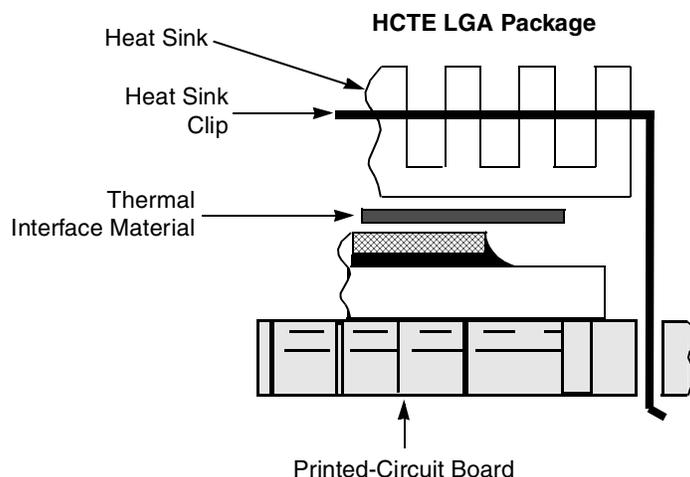


Figure 23. LGA Package Exploded Cross-Sectional View with Several Heat Sink Options

There are several commercially-available heat sinks for the MPC7448 provided by the following vendors:

Aavid Thermalloy 80 Commercial St. Concord, NH 03301 Internet: www.aavidthermalloy.com	603-224-9988
Alpha Novatech 473 Sapena Ct. #12 Santa Clara, CA 95054 Internet: www.alphanovatech.com	408-567-8082
Calgreg Thermal Solutions 60 Alhambra Road, Suite 1 Warwick, RI 02886 Internet: www.calgregthermalsolutions.com	888-732-6100
International Electronic Research Corporation (IERC) 413 North Moss St. Burbank, CA 91502 Internet: www.ctscorp.com	818-842-7277
Tyco Electronics Chip Coolers™ P.O. Box 3668 Harrisburg, PA 17105-3668 Internet: www.tycoelectronics.com	800-522-6752
Wakefield Engineering 33 Bridge St. Pelham, NH 03076 Internet: www.wakefield.com	603-635-2800

Ultimately, the final selection of an appropriate heat sink depends on many factors, such as thermal performance at a given air velocity, spatial volume, mass, attachment method, assembly, and cost.

of any thermal interface material depends on many factors—thermal performance requirements, manufacturability, service temperature, dielectric properties, cost, and so on.

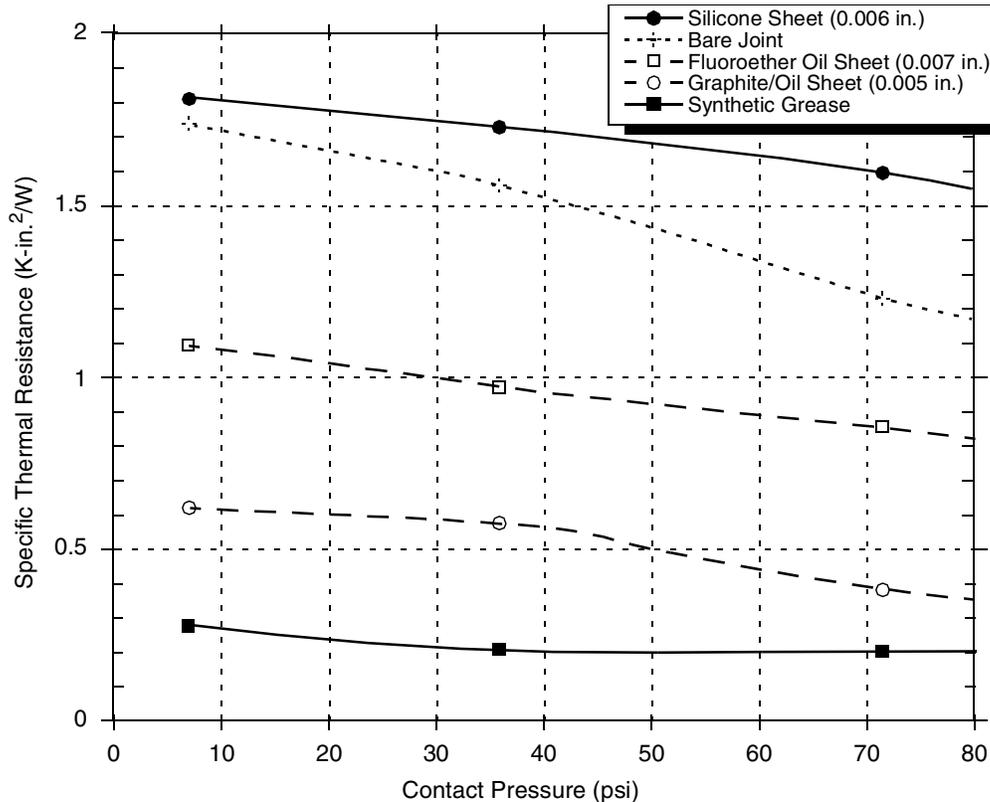


Figure 25. Thermal Performance of Select Thermal Interface Material

The board designer can choose between several types of thermal interfaces. Heat sink adhesive materials should be selected based on high conductivity and mechanical strength to meet equipment shock/vibration requirements. There are several commercially available thermal interfaces and adhesive materials provided by the following vendors:

The Bergquist Company 18930 West 78 th St. Chanhassen, MN 55317 Internet: www.bergquistcompany.com	800-347-4572
Chomerics, Inc. 77 Dragon Ct. Woburn, MA 01801 Internet: www.chomerics.com	781-935-4850
Dow-Corning Corporation Corporate Center P.O. Box 994. Midland, MI 48686-0994 Internet: www.dowcorning.com	800-248-2481

9.7.4 Temperature Diode

The MPC7448 has a temperature diode on the microprocessor that can be used in conjunction with other system temperature monitoring devices (such as Analog Devices, ADT7461™). These devices use the negative temperature coefficient of a diode operated at a constant current to determine the temperature of the microprocessor and its environment. For proper operation, the monitoring device used should auto-calibrate the device by canceling out the V_{BE} variation of each MPC7448's internal diode.

The following are the specifications of the MPC7448 on-board temperature diode:

$$V_f > 0.40 \text{ V}$$

$$V_f < 0.90 \text{ V}$$

Operating range 2–300 μA

Diode leakage < 10 nA @ 125°C

Ideality factor over 5–150 μA at 60°C: $n = 1.0275 \pm 0.9\%$

Ideality factor is defined as the deviation from the ideal diode equation:

$$I_{fw} = I_s \left[e^{\frac{qV_f}{nKT}} - 1 \right]$$

Another useful equation is:

$$V_H - V_L = n \frac{KT}{q} \left[\ln \frac{I_H}{I_L} \right] - 1$$

Where:

I_{fw} = Forward current

I_s = Saturation current

V_d = Voltage at diode

V_f = Voltage forward biased

V_H = Diode voltage while I_H is flowing

V_L = Diode voltage while I_L is flowing

I_H = Larger diode bias current

I_L = Smaller diode bias current

q = Charge of electron (1.6×10^{-19} C)

n = Ideality factor (normally 1.0)

K = Boltzman's constant (1.38×10^{-23} Joules/K)

T = Temperature (Kelvins)

The ratio of I_H to I_L is usually selected to be 10:1. The previous equation simplifies to the following:

$$V_H - V_L = 1.986 \times 10^{-4} \times nT$$